

# Diamond Power Semiconductor Devices

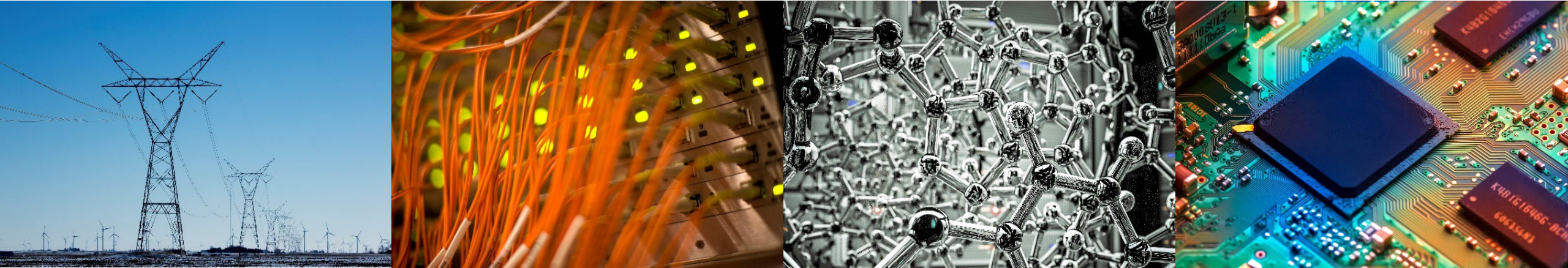
**Zhuoran Han, Jaekwon Lee, and Can Bayram**

[zhuoran5@illinois.edu](mailto:zhuoran5@illinois.edu); [jaekwon2@illinois.edu](mailto:jaekwon2@illinois.edu); [cbayram@illinois.edu](mailto:cbayram@illinois.edu)

Department of Electrical and Computer Engineering

Nick Holonyak, Jr Micro and Nanotechnology Laboratory

University of Illinois at Urbana-Champaign, Illinois, USA



**Evolving Wide Bandgap Materials and Device Technology for Advanced Switching, Microwave and Grid Applications**

**Nov 8<sup>th</sup>, 2024, Virtual**

**I ILLINOIS**

Electrical & Computer Engineering

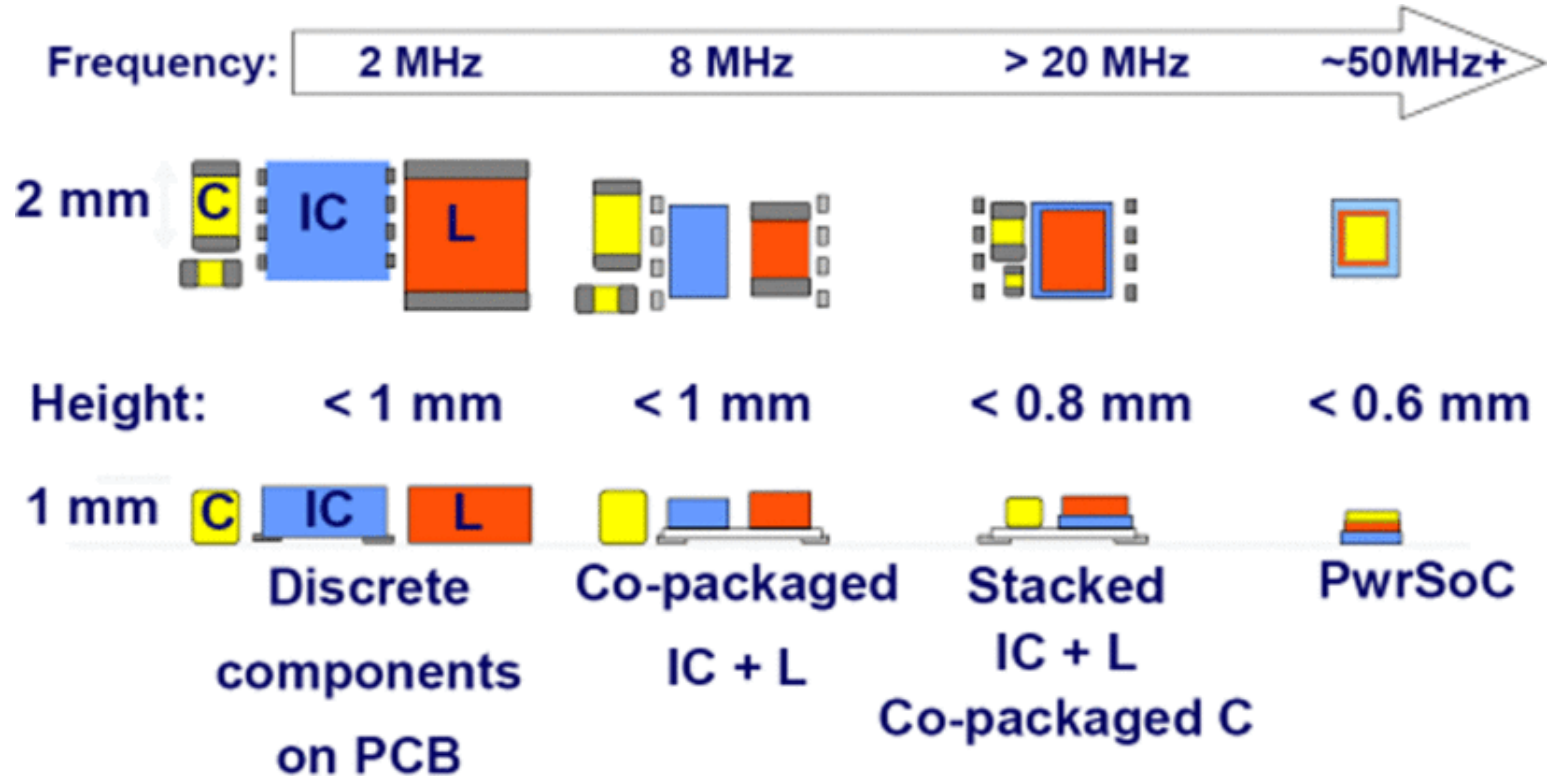
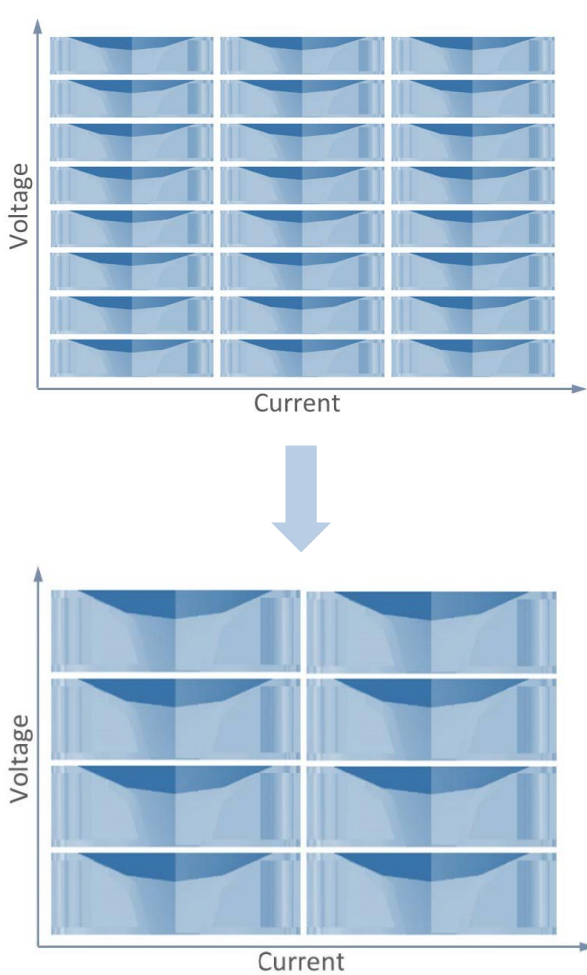
COLLEGE OF ENGINEERING

# Contents

---

- Introduction & Motivation
- Diamond Schottky Power Diodes
- Diamond Photoconductive Switches
- Conclusion & Future work

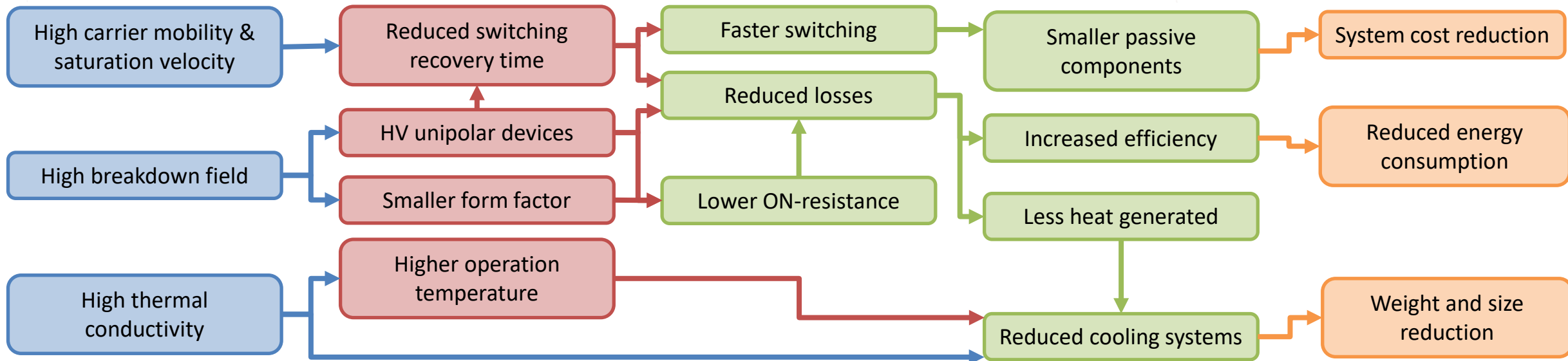
# Motivation: higher voltage, current, and speed discrete devices



- ❖ Improve/simplify circuit realization with fewer higher voltage/current devices/modules
- ❖ Reduce energy storage requirements and passive component sizes

# Ultra-Wide-Bandgap semiconductors: diamond's material advantages

Si	4H-SiC	GaN	$\beta$ -Ga <sub>2</sub> O <sub>3</sub>	AlN	Diamond
----	--------	-----	---	-----	---------



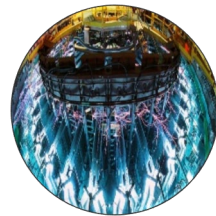
# Diamond power devices: performance advantages & key applications

Next-Gen diamond devices

## Application



High voltage:  
HVDC/UHVDC



Fast actuation:  
Grid-protection  
Pulsed power

## Diamond Devices

Unipolar diodes & transistors

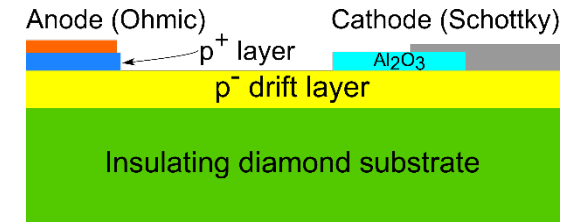
Photo switches

## Performance Benefits

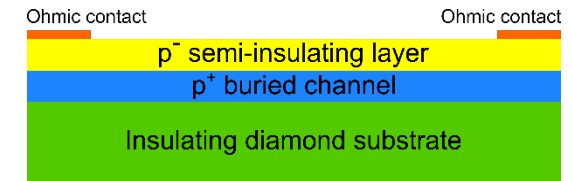
Higher BV  
Faster switching

Longer lifetime  
High slew rates

## Prototype Diamond Devices



5 kV Lateral SBDs



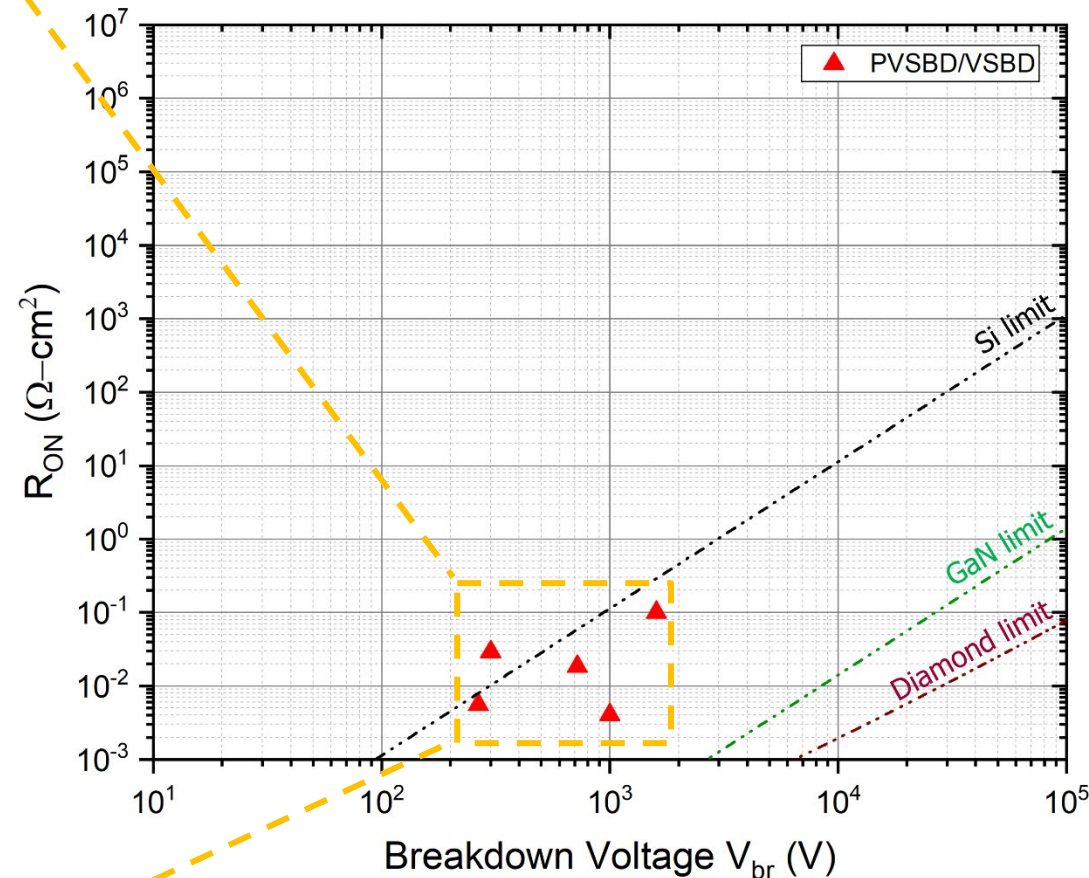
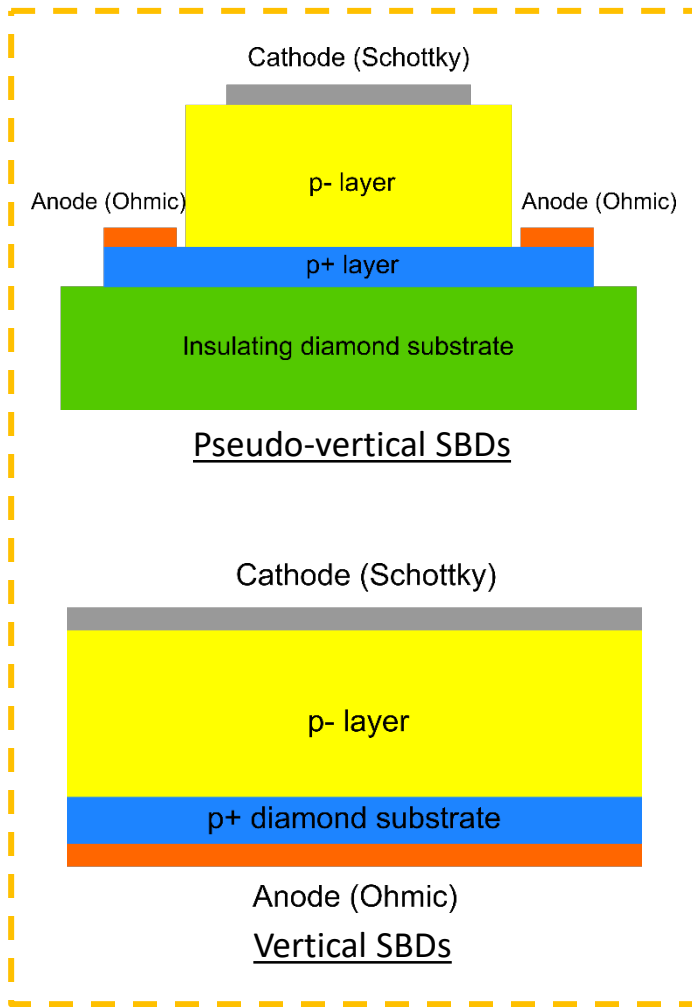
Buried channel PCSS

# Contents

---

- Introduction & Motivation
- Diamond Schottky Power Diodes
- Diamond Photoconductive Switches
- Conclusion & Future work

# Diamond Schottky barrier diodes: vertical vs. Lateral



## Challenges for PVSBD/V SBD:

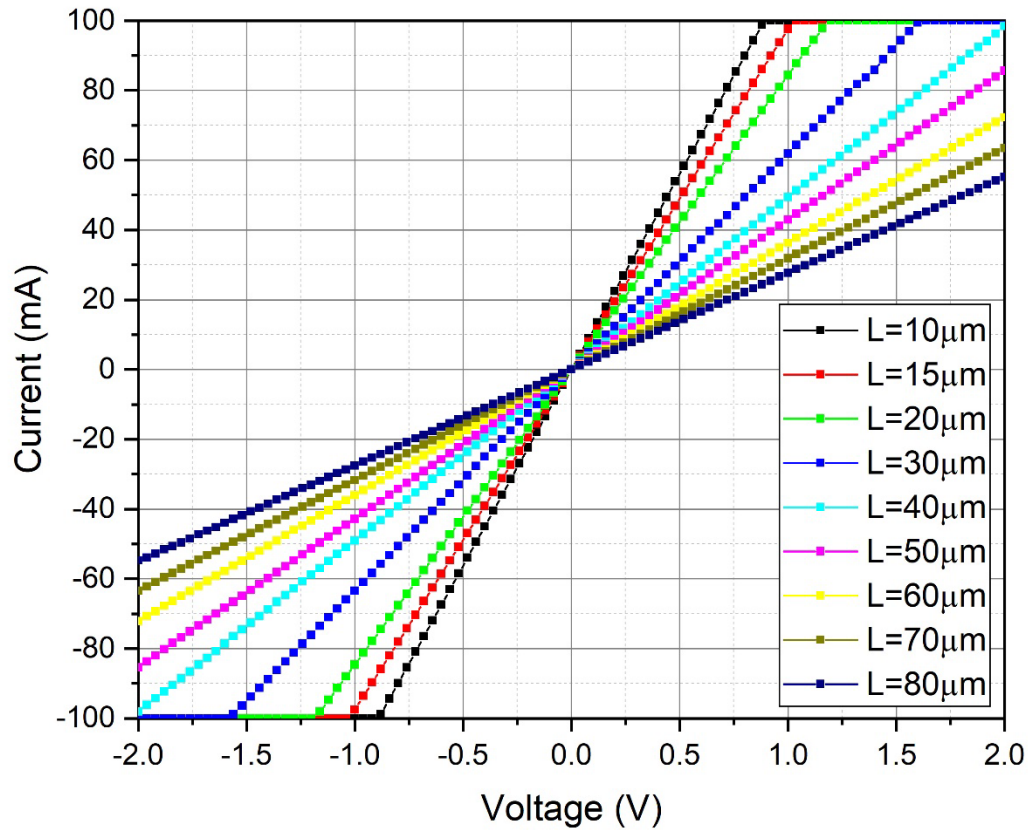
- ❖ Breakdown voltage scales with epitaxial layer thickness
- ❖ PVSBD: Deep dry etching of diamond is difficult & creates processing issues
- ❖ V SBD: Difficult to grow heavily doped substrate; high defect densities

## Solution for >5kV operations:

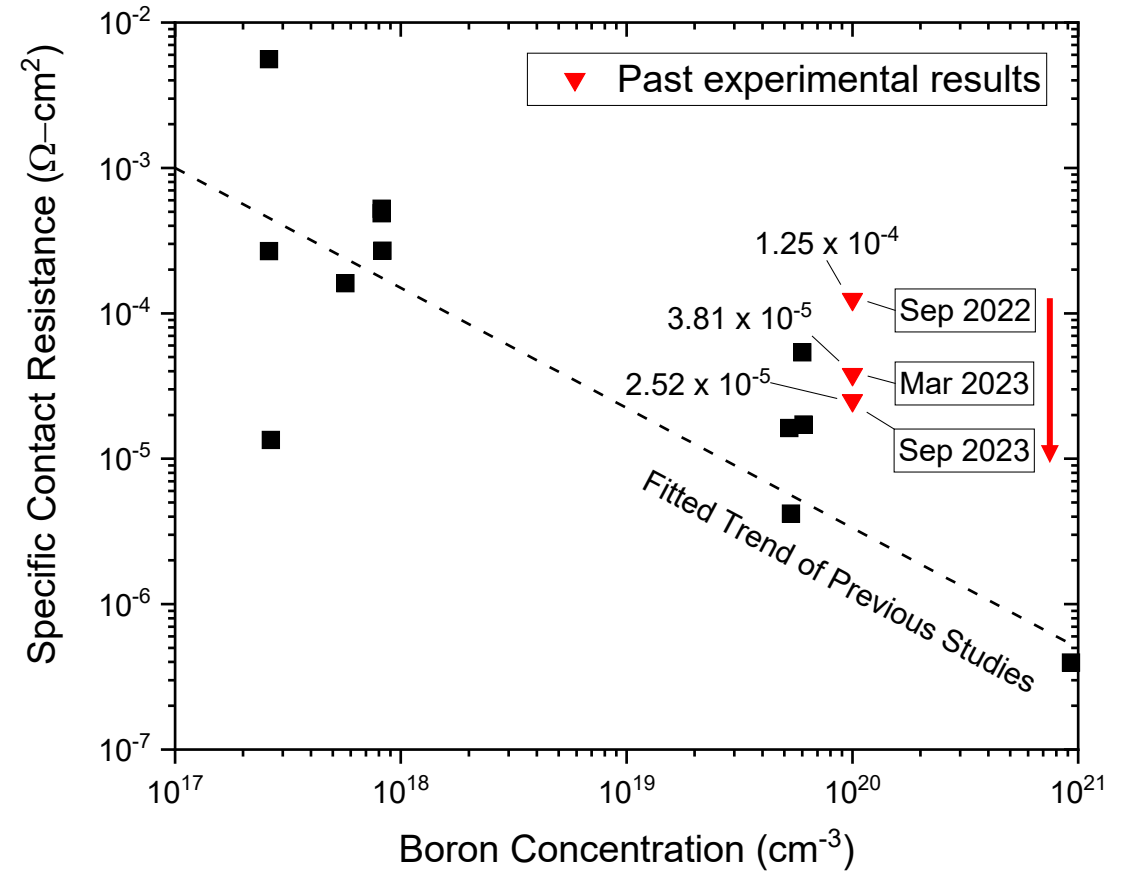
- ❖ Lateral SBD:
  - ✓ Scalability of BV
  - ✓ Does not require thick epitaxial layers



# Ohmic contact on P<sup>+</sup> boron-doped diamond



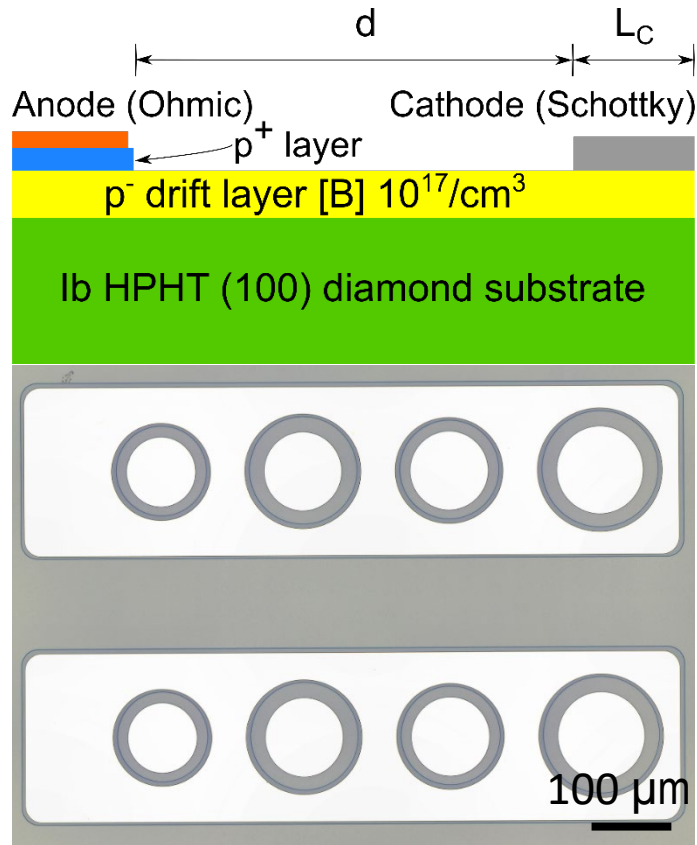
(Left) Optical microscope image of linear TLM patterns; (Right)  $I$ - $V$  measurements from TLM patterns



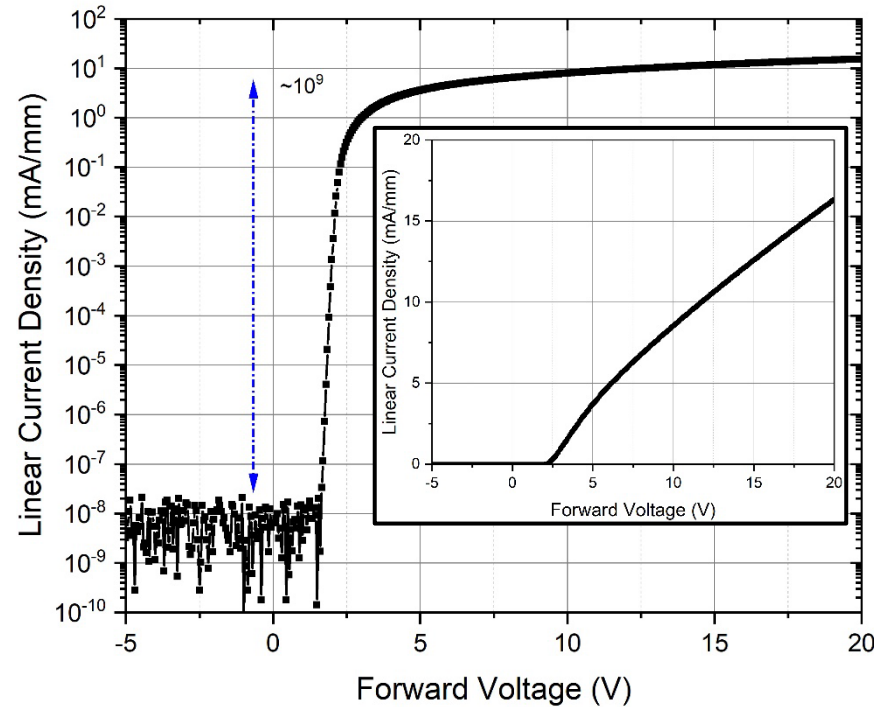
Summary of past experimental results, showing the progress in reducing specific contact resistance



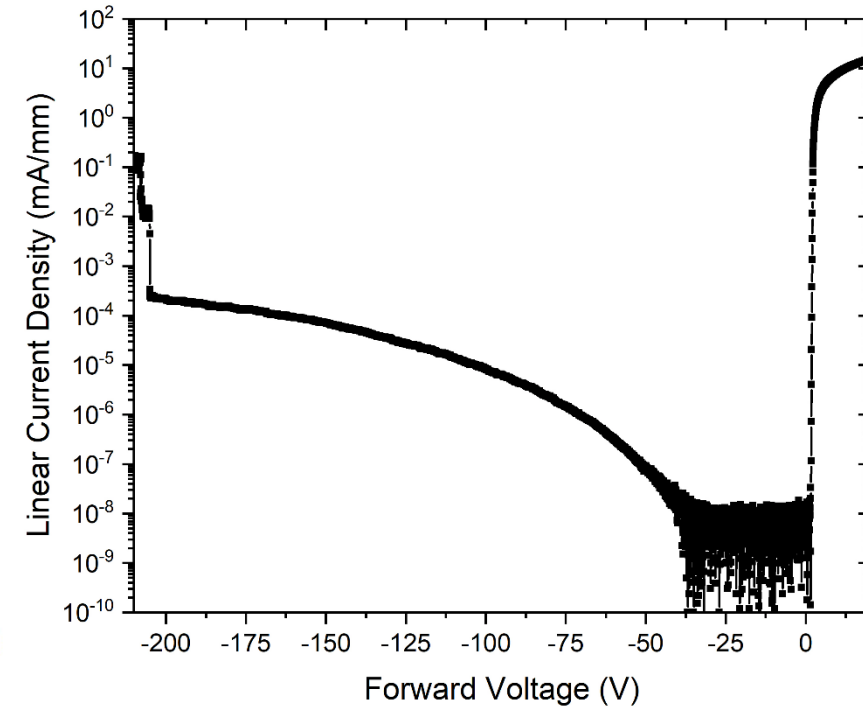
# Schottky contact on P- boron-doped diamond



Cross-section schematic (Top) and top-view microscope image (Right) of lateral Schottky diodes

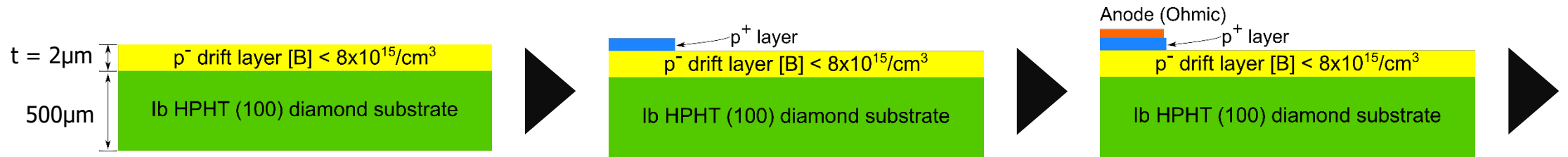


*I-V* characteristics of lateral Schottky diodes at room temperature in semi-log and linear scales



- ❖ Mo-diamond Schottky contacts are fabricated
- ❖ Diode Ideality factor  $\leq 1.20$
- ❖ Rectifying ratio over  $10^9$
- ❖ Peak electric field  $\geq 4$  MV/cm

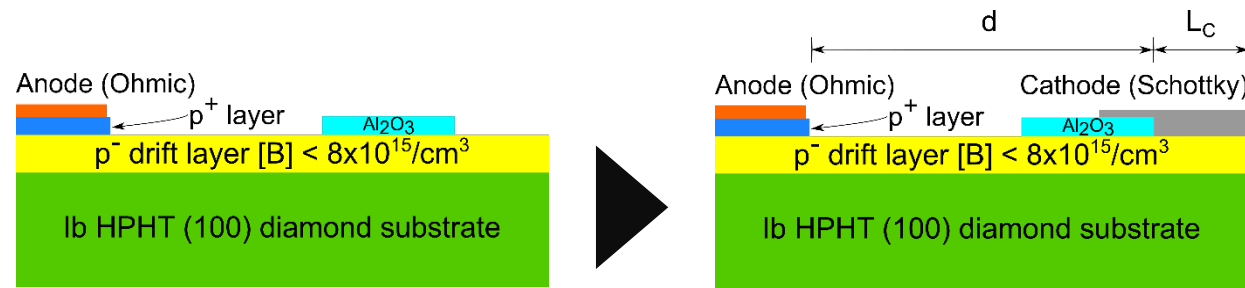
# 4.6 kV Diamond p-type lateral SBDs: Fabrication process



(a) P<sup>-</sup> epitaxial growth

(b) P<sup>+</sup> selective growth

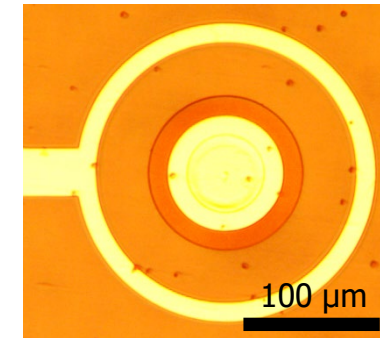
(c) Ohmic contacts deposition



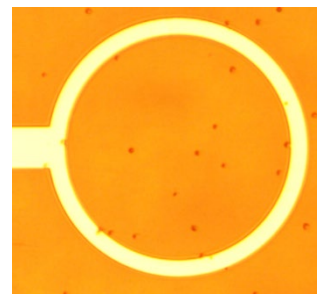
(d) Al<sub>2</sub>O<sub>3</sub> field plates formation

(e) Schottky contacts deposition

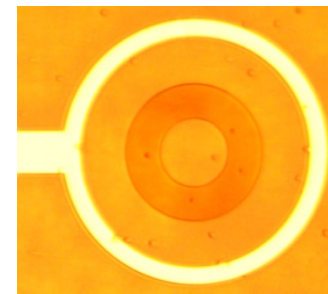
(f) Microscope image of an SBD



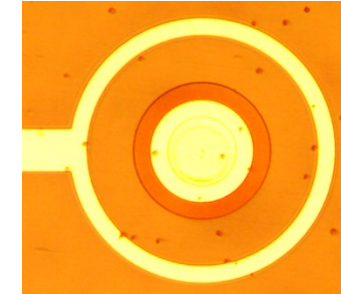
(c)



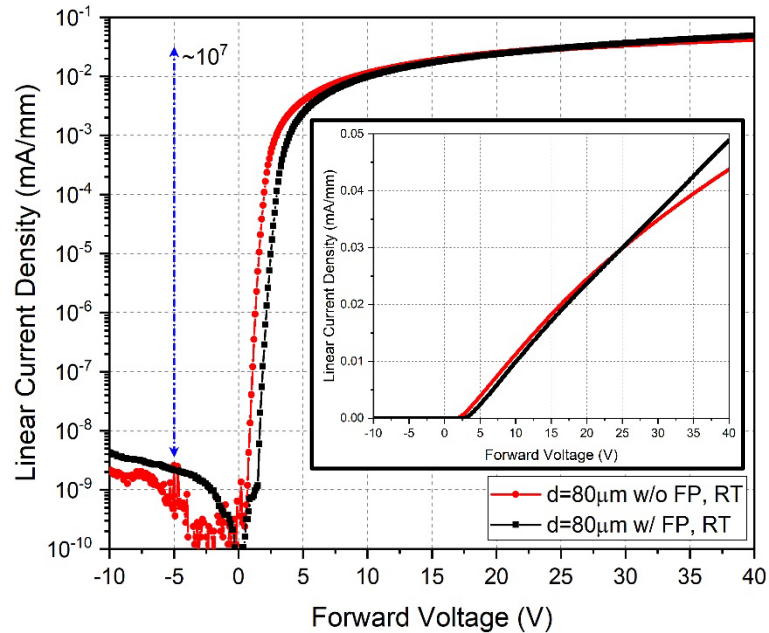
(d)



(e)

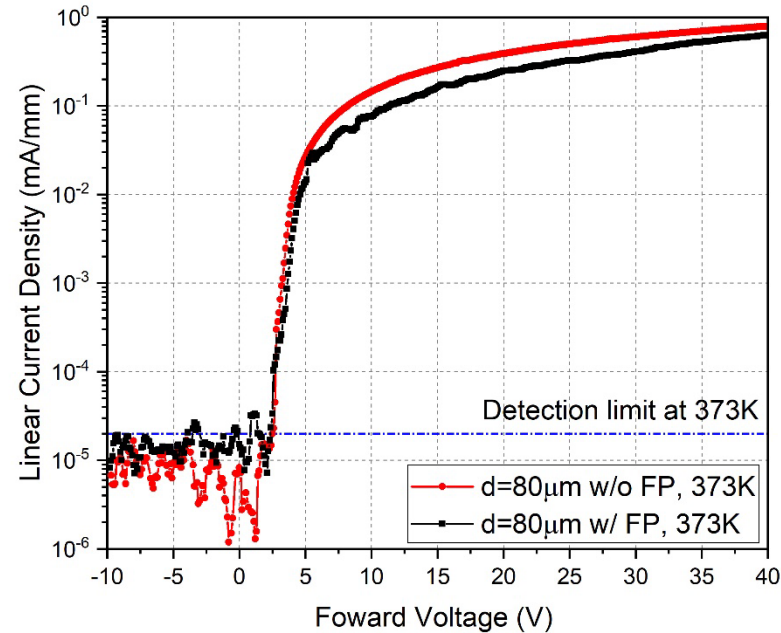


# Diamond p-type lateral SBDs: Forward $I$ - $V$ characteristics



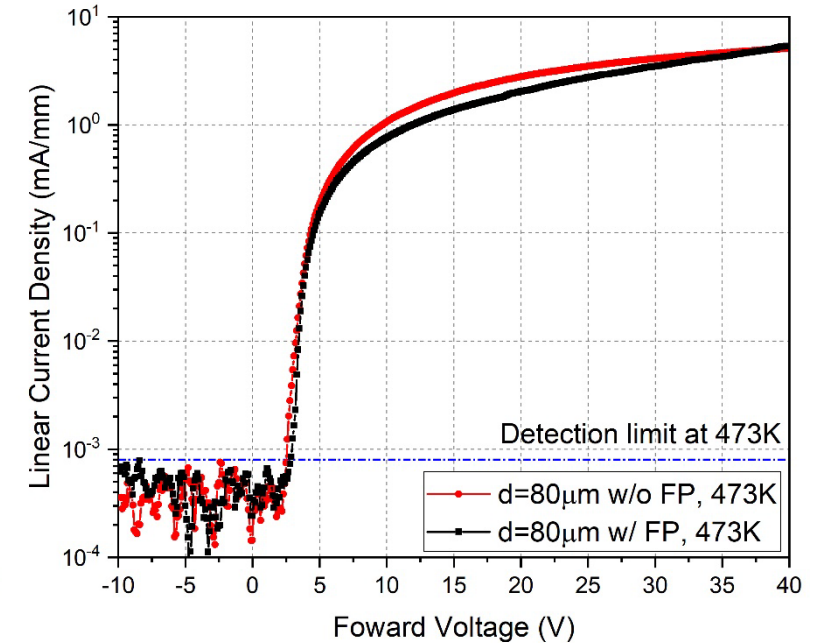
Forward current density at 40V, 300K:

- 0.044 mA/mm w/o FP
- 0.049 mA/mm w/ FP



Forward current density at 40V, 373K:

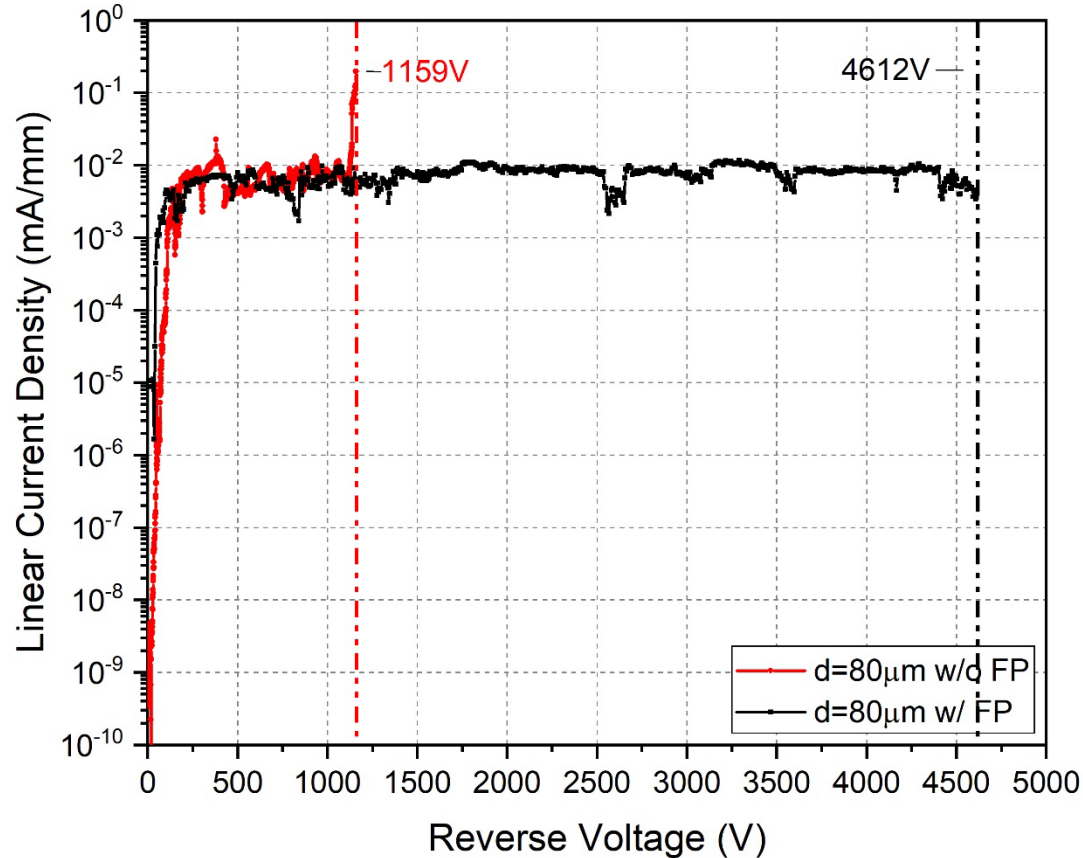
- 0.79 mA/mm w/o FP
- 0.64 mA/mm w/ FP



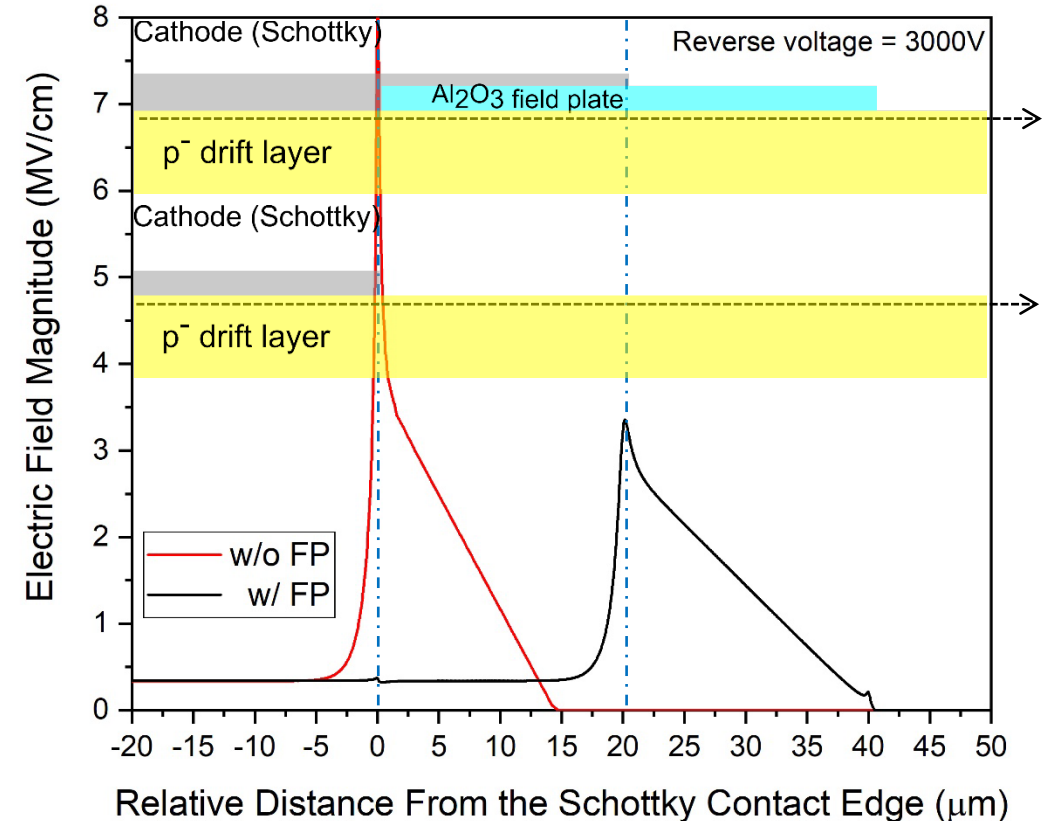
Forward current density at 40V, 473K:

- 5.39 mA/mm w/o FP
- 5.09 mA/mm w/ FP

# Diamond p-type lateral SBDs: Reverse $I$ - $V$ characteristics



With the  $\text{Al}_2\text{O}_3$  FP added, breakdown voltage improved from 1159V to over 4612V (limit of setup)



TCAD Simulation predicts a 56% reduction in peak electric field with the  $\text{Al}_2\text{O}_3$  field plate added

# Summary & Benchmark

## Performance goal

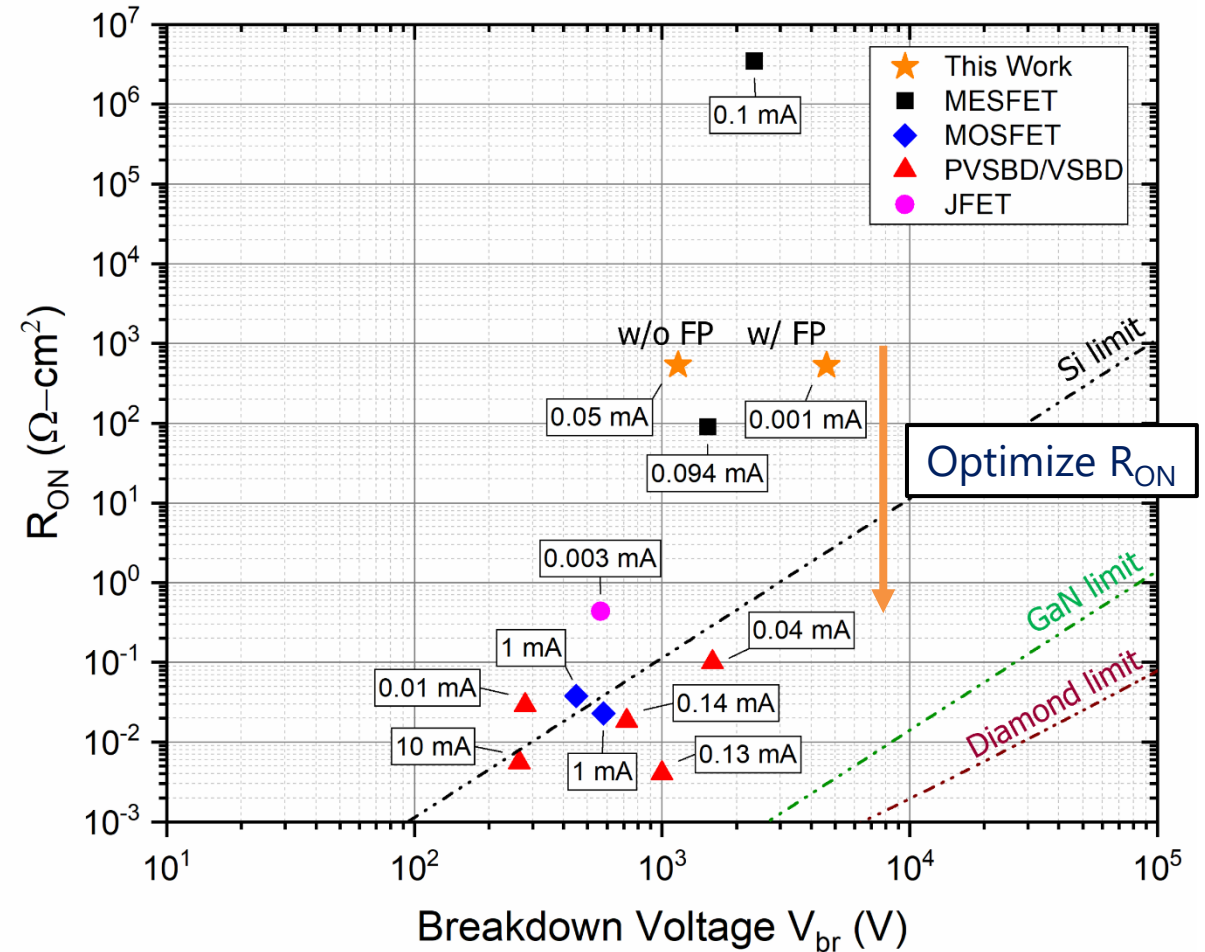
- ❖ 5kV diamond power diodes

## Approach

- ❖ Lateral Schottky diodes
- ❖ Contact regrowth
- ❖ Edge termination

## Results

- ❖ >4.6kV breakdown voltage
- ❖ Low contact resistance
- ❖ Improved performance at high temperature conditions



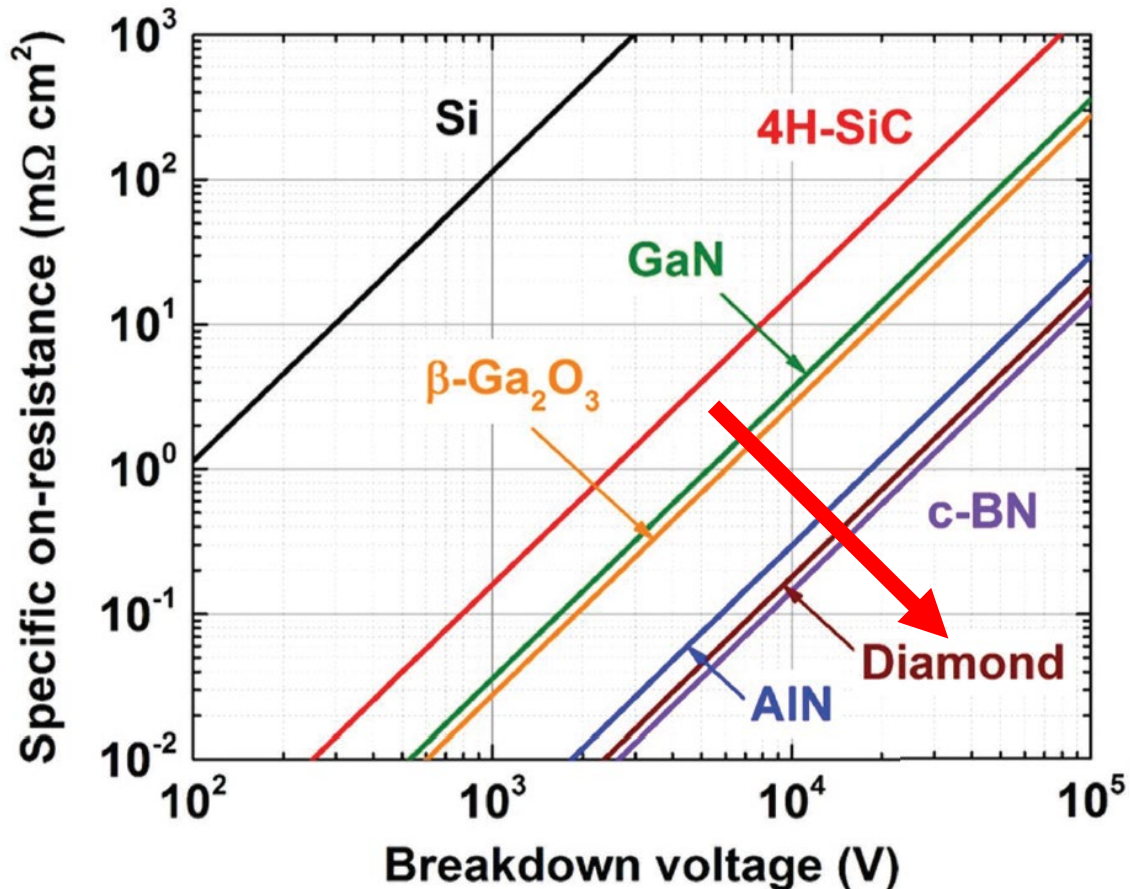
# Contents

---

- Introduction & Motivation
- Diamond Schottky Power Diodes
- Diamond Photoconductive Switches
- Conclusion & Future work

# Reaching diamond's material limit with novel power devices

## How to reach BFOM limits of UWBG materials?



Contours of constant Baliga figure-of-merit (BFOM)

### Challenges for reaching diamond's limit:

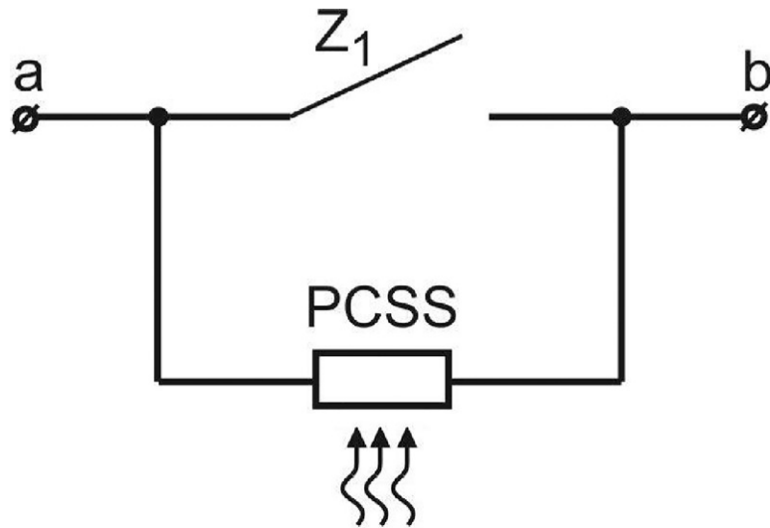
- ❖ Poor dopant incorporation efficiency at room temperature
- ❖ P-type boron activation energy: 0.38 eV from valence band maximum
- ❖ N-type phosphorous activation energy: 0.57 eV from conduction band minimum

### Solutions for reaching low on-resistance:

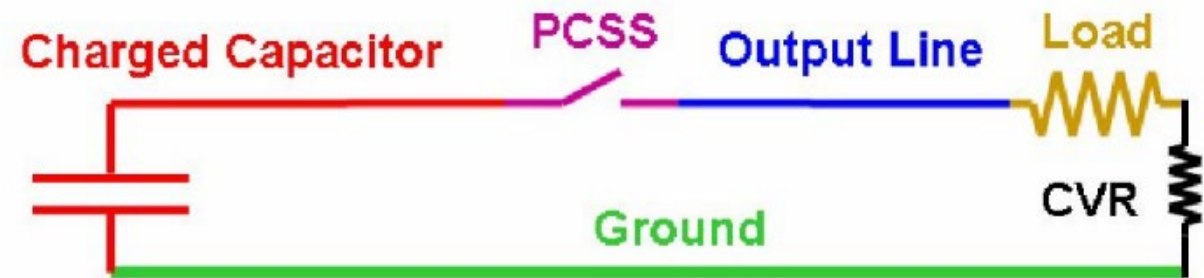
- ❖ Introduce extrinsic carriers through optical excitations
  - ✓ Bipolar conduction
  - ✓ High carrier mobility due to the lack of impurity scattering
  - ✓ Fast response (~ns) and high voltage packaging

# Photoconductive semiconductor switches (PCSS)

- ❖ PCSS utilize photoconductivity for switching between on / off state
- ❖ Application: **Hybrid power switch**, **Trigger generators**, **Power grid protection** etc.



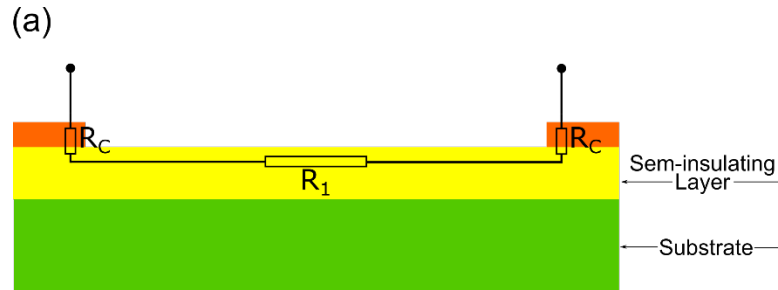
PCSS application in a hybrid power switch



PCSS application in a capacitive discharger pulser



# Buried channel PCSS concept: theory



- Effective circuit model of **(a)** conventional PCSS without the buried channel and **(b)** buried channel PCSS.
- Current density distribution in logarithmic scale based on TCAD simulation inside **(c)** a conventional PCSS and **(d)** a buried channel PCSS under the same condition as **(c)**.

Equivalent circuit model:

- Conventional PCSS:

$$R_{conventional} = 2R_C + R_1$$

- Buried channel PCSS:

$$R_{buried\ channel} = 2R_C + \frac{R_1(2R_2 + R_3)}{R_1 + 2R_2 + R_3}$$

- ✓ Lower on-resistance thanks to the low-resistivity channel
- ✓ During ON-state, most current flows through the buried channel

# Buried channel PCSS: experiment

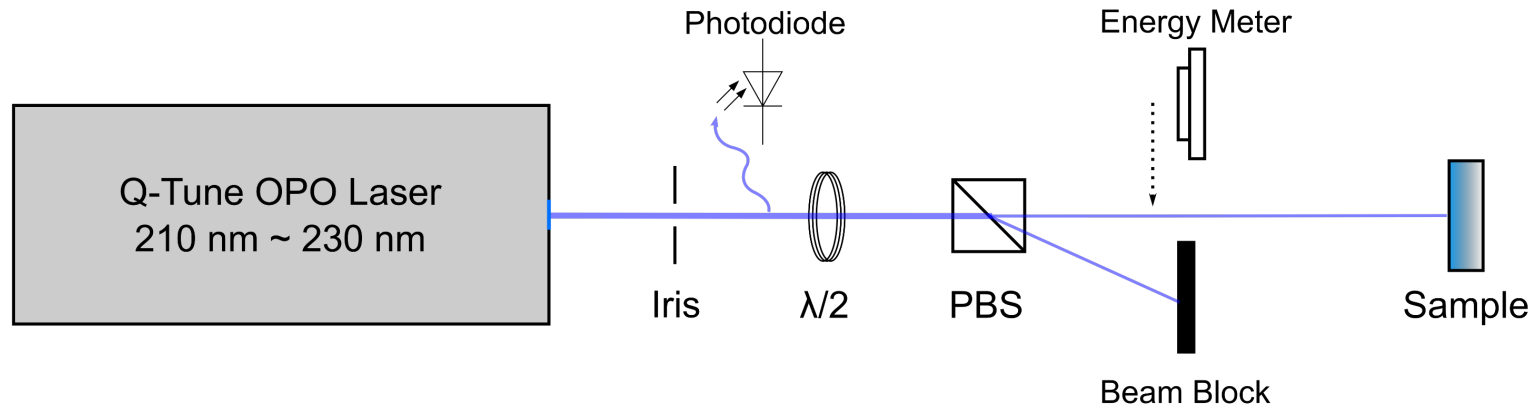
---



Type IIa HPHT  
Diamond  
substrate

500  $\mu\text{m}$  thickness

# Buried channel PCSS: measurement setup

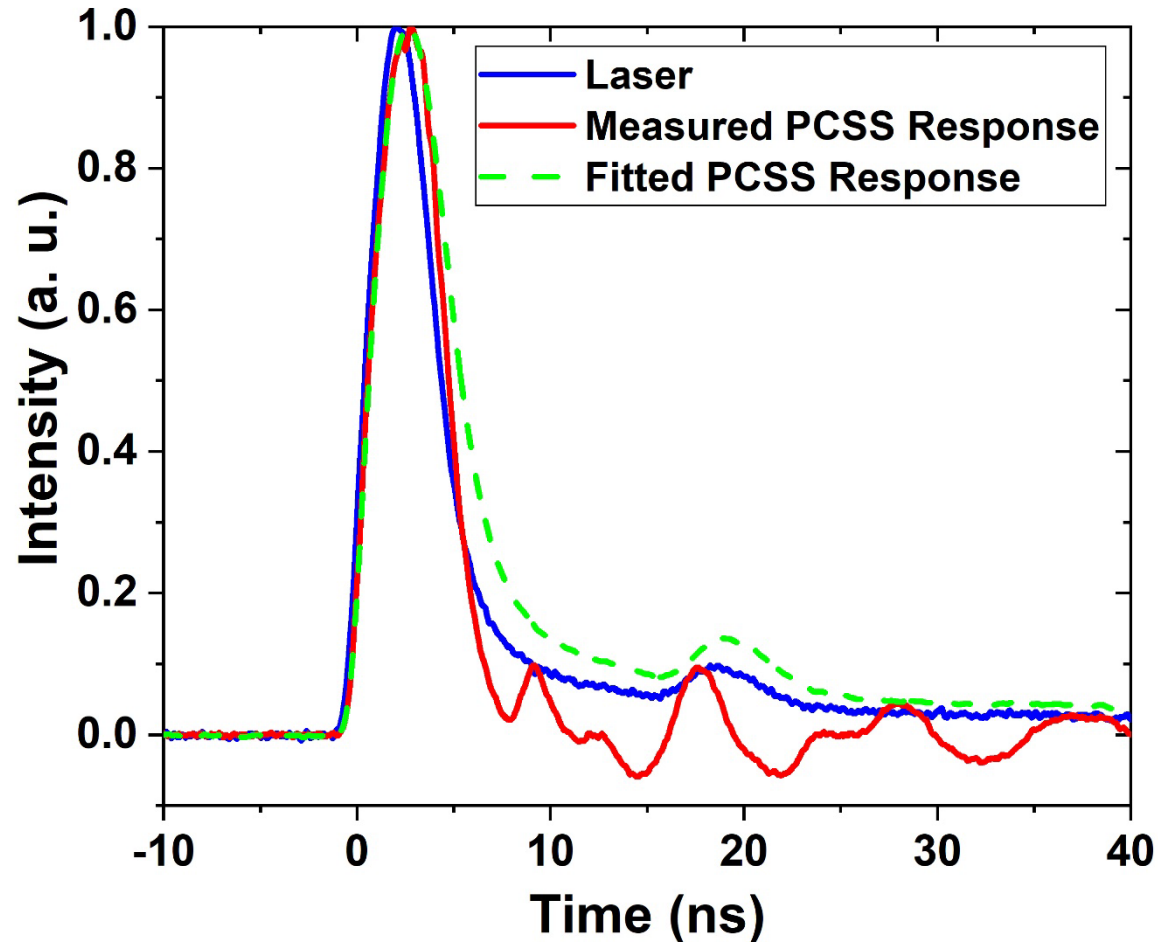


Optical setup used to measure the PCSS device performance

- OPO: optical parametric oscillator
- $\lambda/2$ : half-wave plate
- PBS: polarizing beam splitter

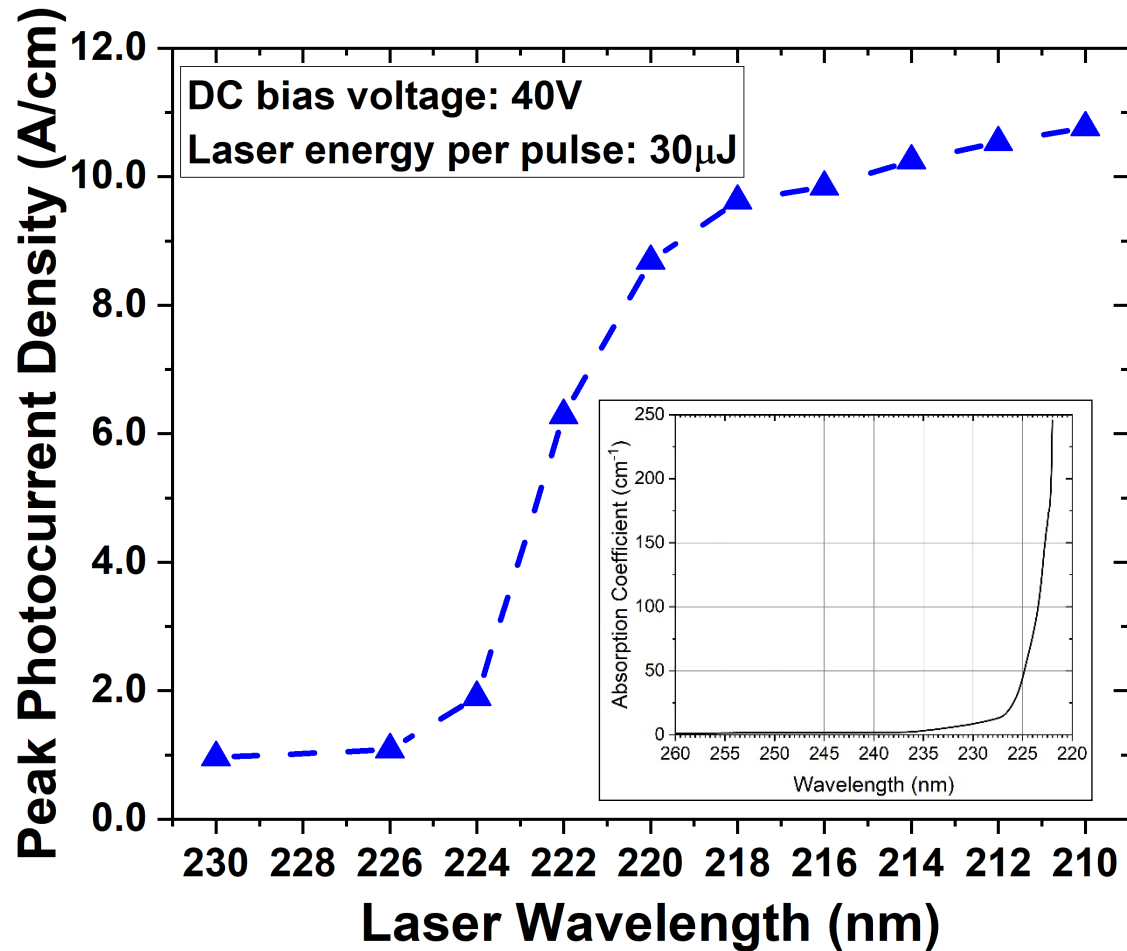
Electrical setup used to measure the PCSS device performance

# Photo response: rise/fall time & carrier lifetime



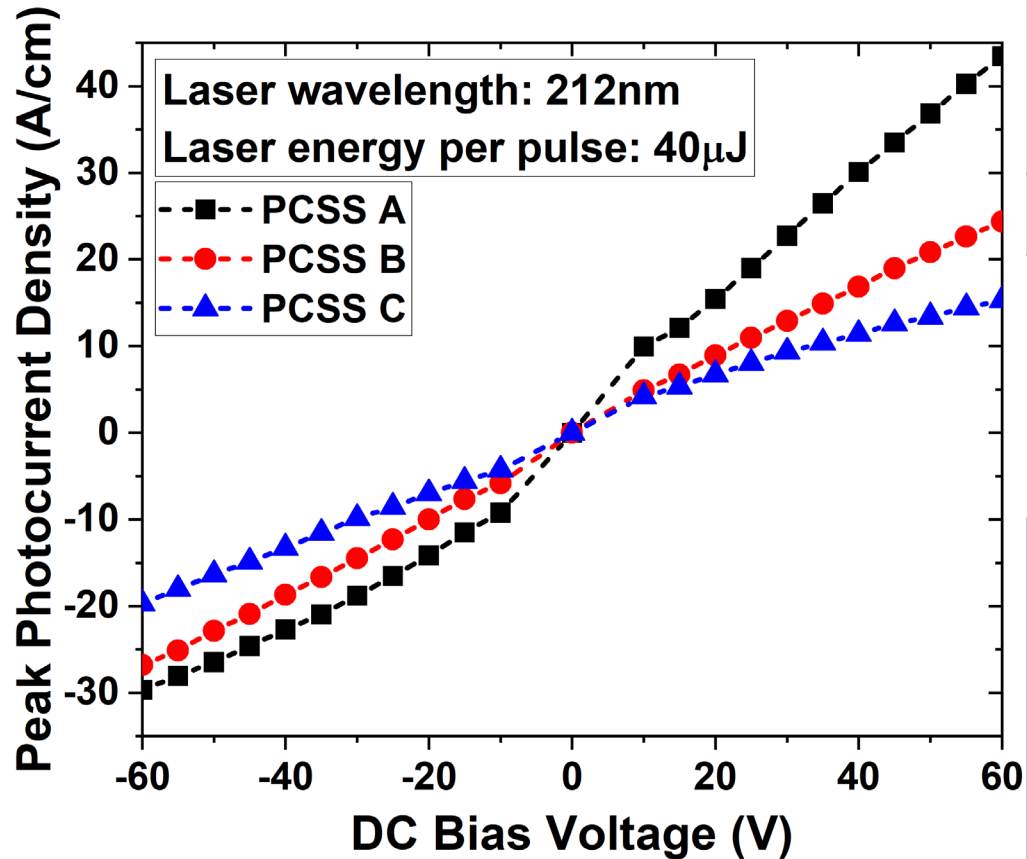
- Laser spectral range: 210 nm - 230 nm
- Spectral width: < 0.1 nm
- Laser pulse width: 4 ns
- Repetition rate: 10 Hz
- Estimated carrier lifetime in PCSS:  $\tau \approx 0.5$  ns
- PCSS response follows closely with optical trigger signal, promising high slew rate when bias voltage is scaled up

# Photo response: wavelength dependent characteristics



- Photocurrent increases significantly above diamond's bandgap (< 226 nm)
- Finding: above-bandgap excitations are advantageous for lateral diamond PCSS

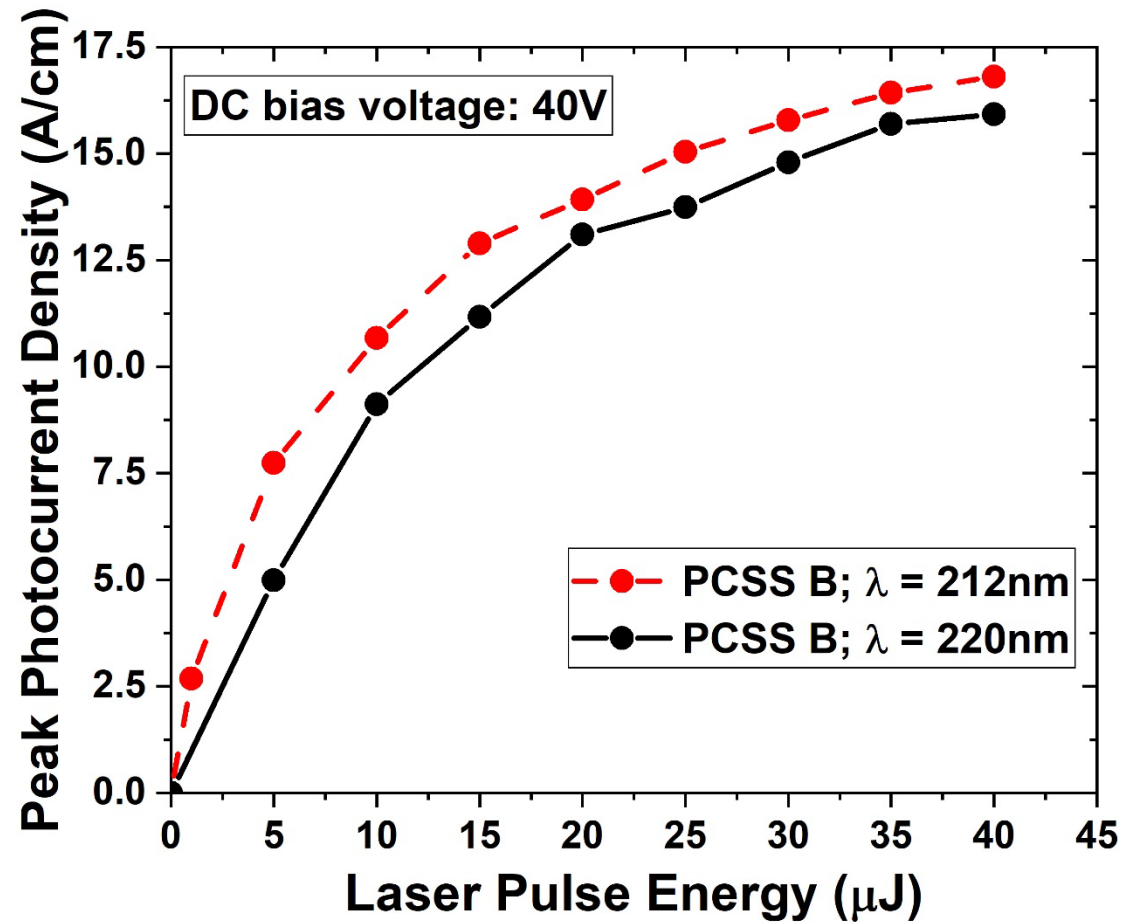
# Photo response: voltage-current characteristics



#	Spacing (µm)	$R_{OFF}$ (GΩ)	$R_{ON}$ (Ω)	$\frac{R_{OFF}}{R_{ON}}$	Peak $J$ (A/cm)	Normalized Responsivity (mA-cm/W-kV)
A	8	0.24	72.1	$3.3 \times 10^6$	43.5	3.55

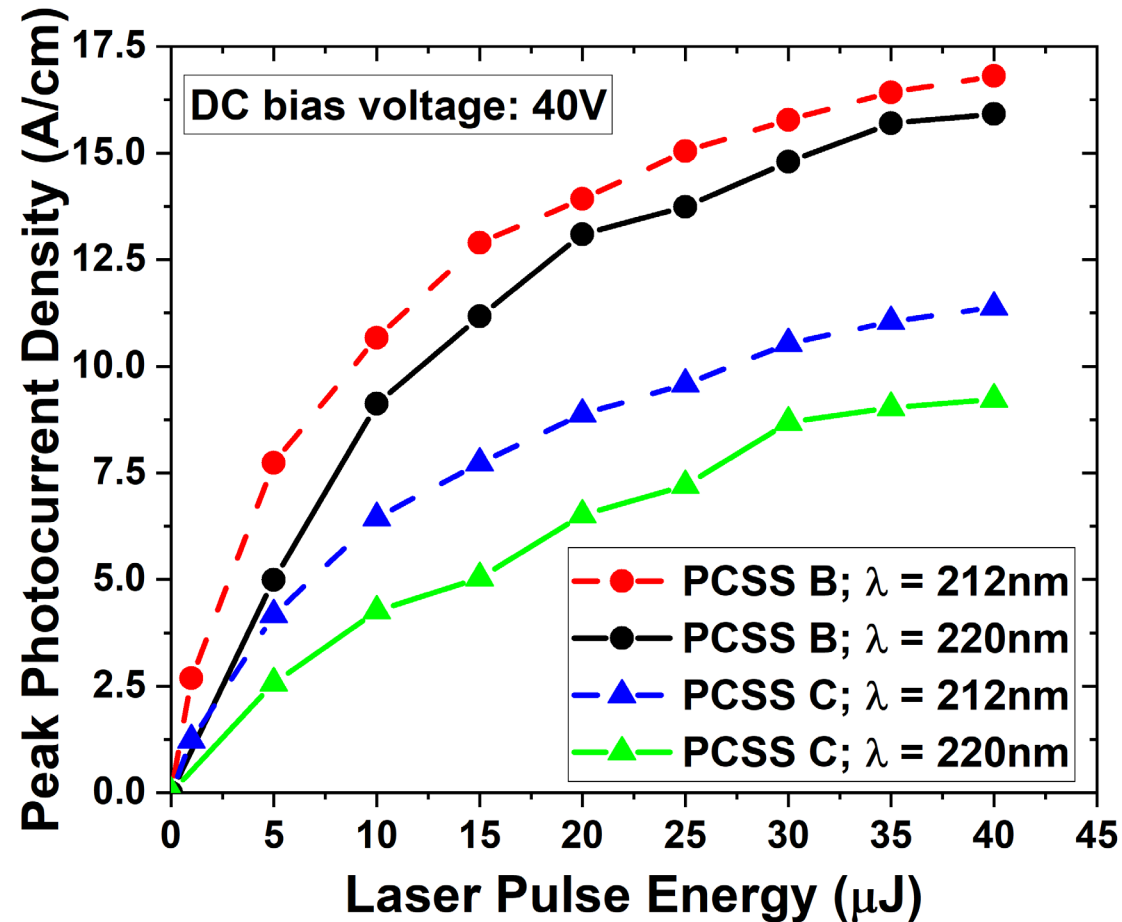
- ✓ Highest current density achieved: **43.5 A/cm** at 60 V
- ✓ Highest Responsivity achieved: **130 mA/W** at 60 V
- ✓ Highest on/off ratio achieved:  **$3.3 \times 10^{11}$**  at 60 V
- ✓ No current saturation observed in all devices
- ✓ Linear  $I$ - $V$  characteristics for +/- bias

# Photo response: optical power dependent characteristics



- At 212 nm and 220 nm, photocurrent saturates at high optical power due to invariant resistances in contacts and the buried channel
- Invariant resistance in PCSS B: **113  $\Omega$**

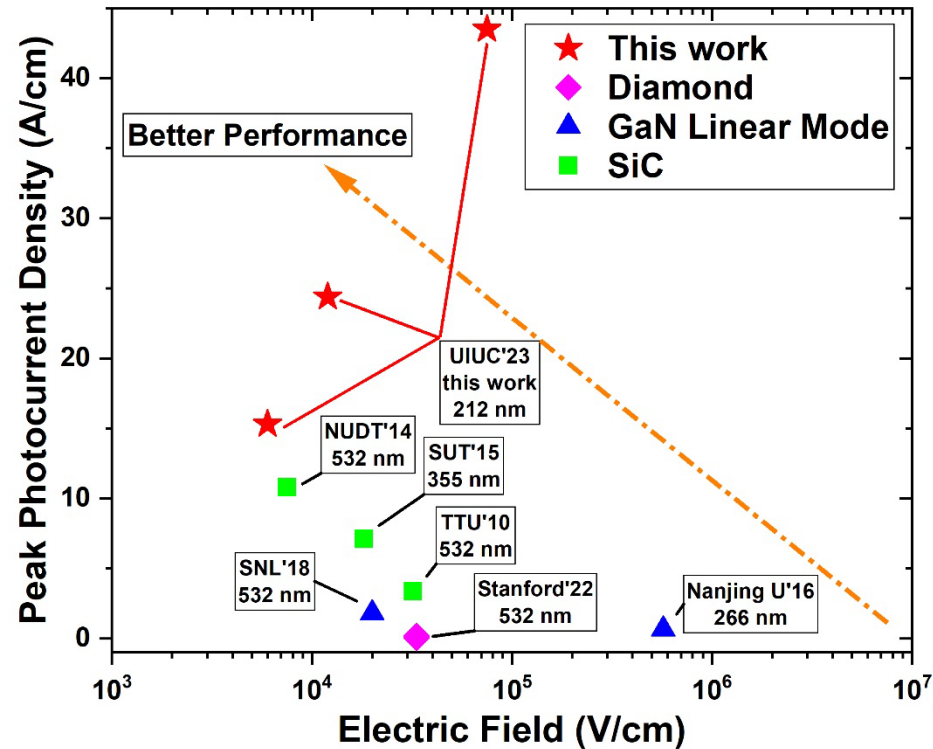
# Photo response: optical power dependent characteristics



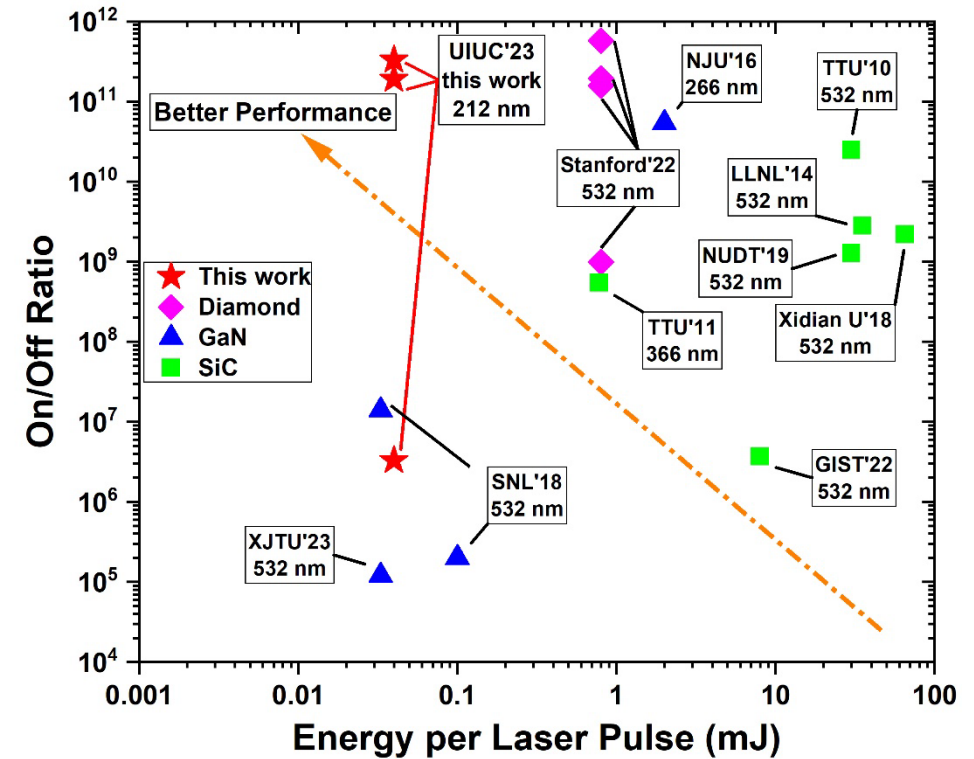
- At 212 nm and 220 nm, photocurrent saturates at high optical power due to invariant resistances in contacts and the buried channel
- Invariant resistance in PCSS B: **113  $\Omega$**
- Invariant resistance in PCSS C: **154  $\Omega$**
- Calculated resistances predict that between **91%** to **93%** of current conduction is through the buried channel



# Summary & Benchmark



Benchmark of PCSS in terms of photocurrent density vs. lateral E-field



Benchmark of PCSS in terms of on/off ratio vs. energy per laser pulse

- ✓ **High current density** in linear mode at low optical power & electric field
- ✓ **~ns rise/fall time** and **> 10<sup>11</sup> on/off ratio**

# Contents

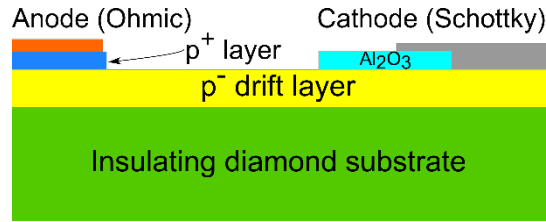
---

- Introduction & Motivation
- Diamond Schottky Power Diodes
- Diamond Photoconductive Switches
- Conclusion & Future work

# Conclusion & future work

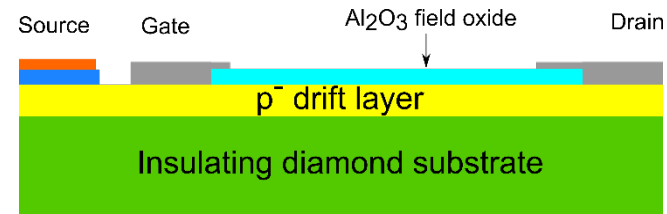


High voltage:  
HVDC/UHVDC



Lateral SBDs

- 5kV BV
- Stable at high temperature



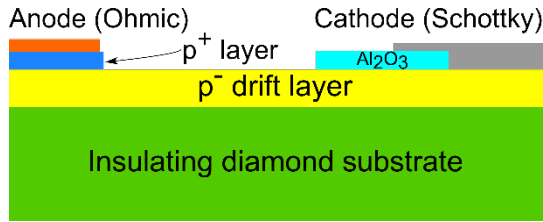
Reverse-blocking MESFETs

- Current work
- 10kV BV
- Low gate leakage

# Conclusion & future work

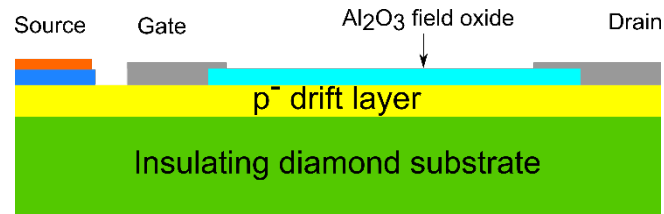


High voltage:  
HVDC/UHVDC



Lateral SBDs

- 5kV BV
- Stable at high temperature

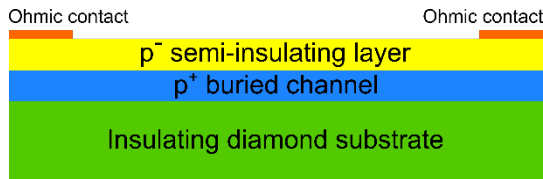


Reverse-blocking MESFETs

- Current work
- 10kV BV
- Low gate leakage



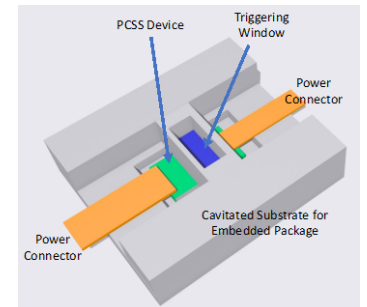
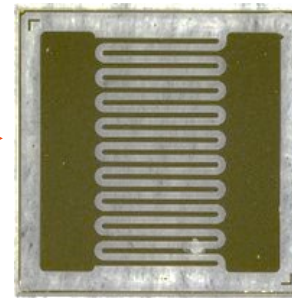
Fast switching:  
Grid-protection



Buried channel PCSS

- 43.5A/cm current density
- $> 10^{11}$  on/off ratio

Scale-up



- Slew rate:  $\geq 500$  V/ns,  $\geq 200$  A/ns
- 20 kV BV
- $\geq 5$  A per die

# Acknowledgements

## Our work is partially supported by

- Coherent / II-VI Foundation
- Advanced Research Projects Agency–Energy (ARPA-E), under award number DE-AR0001846
- Office of Naval Research (ONR), under award number 13235235
- Applied Research Institute (ARI) / Silicon Crossroads Microelectronics Commons (SCMC) Hub
- University of Illinois Urbana-Champaign ECE Distinguished Research Fellowship
- University of Illinois Urbana-Champaign ECE Promise of Excellence Fellowship
- Andrew T. Yang Research and Entrepreneurship Award
- Nick and Katherine Holonyak Jr. Outstanding Research Award
- SPIE Optics and Photonics Scholarship



# Publications & patents

## ❖ Journal Papers:

- Z. Han, J. Lee, S. Messing, T. Reboli, A. Mironov, and C. Bayram, “**Buried Channel Diamond Photoconductive Switch with High Above-Bandgap Responsivity,**” (2024), *IEEE Electron Device Letters* (Top downloaded article)
- Z. Han, and C. Bayram, “**Diamond p-type Lateral Schottky Barrier Diodes with High Breakdown Voltage (> 4.6 kV at 0.01 mA/mm),**” (2023), *IEEE Electron Device Letters* (Top downloaded article)
- J. Lee, C. Bayram, and J.P. Leburton, “**High Field Transport in (Ultra) Wide Bandgap Semiconductors: Diamond Versus Cubic GaN,**” (2024), *IEEE Transactions on Electron Devices* (Top downloaded article)

## ❖ Patents:

- Can Bayram, Jae Kwon Lee, Andrey Mironov, and Zhuoran Han **LIGHT-TRIGGERED DIAMOND SWITCHES** (Application No.: 63/530,434)
- Can Bayram, and Zhuoran Han **BIDIRECTIONAL DIAMOND DEVICES** (Application No.: 63/609,000)
- Can Bayram, Jae Kwon Lee, and Zhuoran Han **BURIED CHANNEL PHOTOCONDUCTIVE SWITCH** (Application No.: 63/531,298)

**Thank you!**

